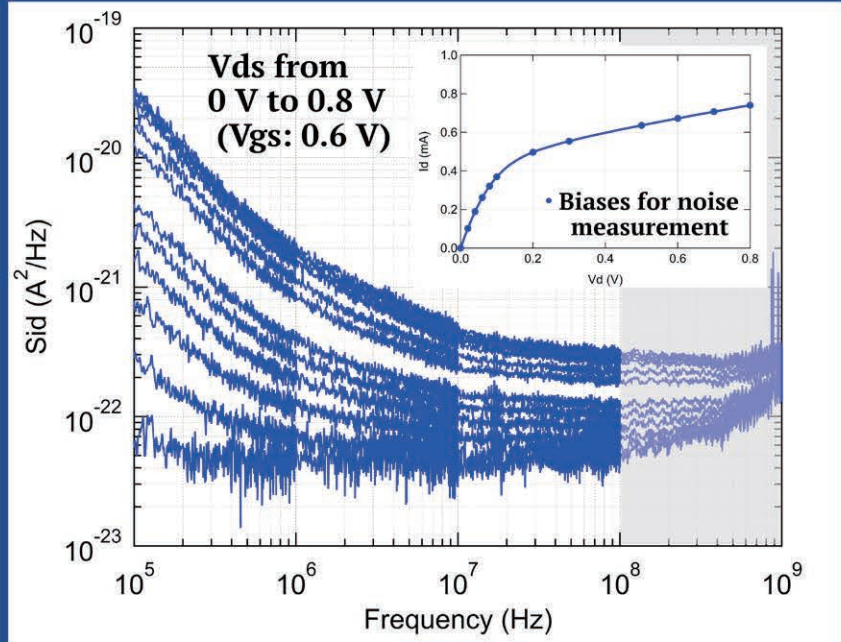
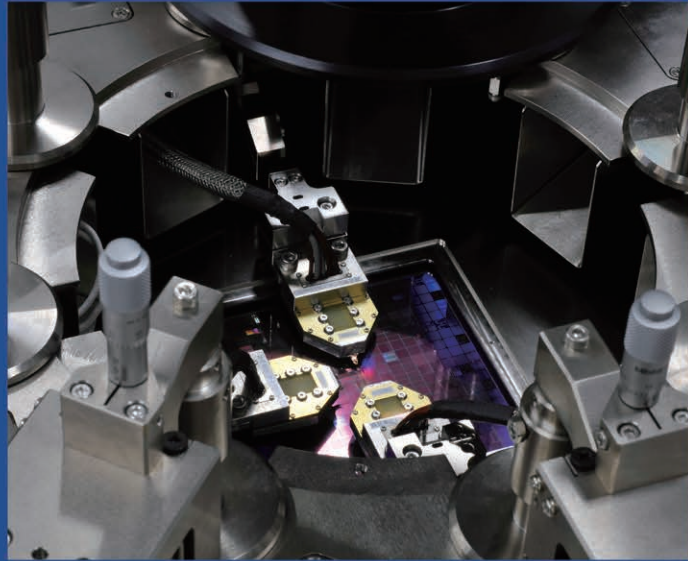


# Entrope™ High-Frequency Noise Probe System

Entrope™ Probe (patented)

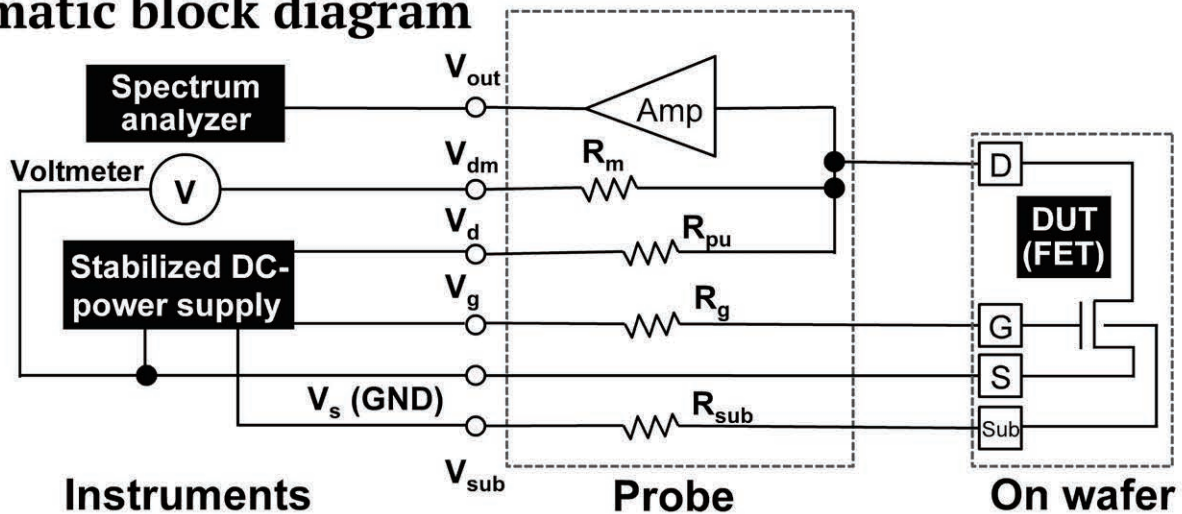
Example: n-MOSFET (Lg: 120 nm)



## Specification

Probe type	Frequency	Floor noise (minimum)
Entrope™ 101A	100k - 100MHz	~3×10 <sup>-23</sup> (A <sup>2</sup> /Hz) @ 10 MHz
Entrope™ 102A	100k - 100MHz	~5×10 <sup>-23</sup> (A <sup>2</sup> /Hz) @ 10 MHz

## Schematic block diagram



**Entrope™ Noise Probe System** dramatically extends the frequency range of noise measurements compared to conventional low-frequency (1/f) noise measurement systems. The probe tips are configured in order to suit your DUTs.

- Thermal/shot noise evaluation
- RTN and 1/f noise measurements at high frequencies
- Measurement-based SPICE noise models and predictive circuit design

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